Notice of References Cited Application/Control No. 10/575,289 Applicant(s)/Patent Under Reexamination VAN LIER ET AL. Examiner SHEELA C. CHAWAN Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,475,507	12-1995	Suzuki et al.	358/500
*	В	US-5,287,293	02-1994	Chen et al.	702/40
*	С	US-5,379,350	01-1995	Shimazu et al.	382/197
*	D	US-5,579,405	11-1996	Ishida et al.	382/197
*	Е	US-5,774,595	06-1998	Kim, Jin-Hun	382/241
	F	US-			
	O	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	>						
	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.